

PATENT APPLICATION
Do. No. 9903-011

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Chang-Nyun KIM, et al.

Serial No.

09/752,998

Examiner:

Karlsen, Ernest F

Filed:

December 28, 2000

Group Art Unit: 2829

For:

METHOD AND APPARATUS FOR TESTING SEMICONDUCTOR DEVICES USING THE BACK SIDE OF A CIRCUIT BOARD

Assistant Commissioner for Patents, Washington, D.C. 20231

Responsive to the Office Action dated June 21, 2002, enclosed is an amendment in the above-identified application.

The fee has been calculated as shown below.

CLAIMS AS AMENDED					
For:	Number After Amendment	Previous Number	Extra	Rate	Additional Fee
Total Claims	29	25	4	x \$18 =	\$72
Independent Claims	4	2	1	x \$84 =	\$84
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$156

<sup>\*</sup>greater of twenty (20) or number for which fee has been paid

PTO Form 2038 authorizing credit card payment for the above-listed fees is enclosed.

Any deficiency or overpayment should be charged or credited to deposit account number 13-

Respectfully submitted,

MARGER JOHNSON & McCOLLOM, P.C.

20575

PATENT TRADEMARK OFFICE

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I HEREBY CERTIFY THAT THIS COR-RESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO:

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<sup>\*\*</sup>greater of three (3) or number for which fee has been paid





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**BOX NON FEE AMENDMENT** Assistant Commissioner for Patents Washington, D.C. 20231

## RESPONSE TO OFFICE ACTION

Responsive to the Office Action, dated June 21, 2002, please amend the application as follows.

10/02/2002 SZEWDIE1 00000022 09752998

01 FC:102 02 FC:103

IN THE SPECIFICATION

At page 2, line 8 to line 18, please replace the paragraph with the followings:

FIG. 3 and FIG. 4 are top and side views, respectively, showing another conventional test apparatus 170 which prevents obstruction by peripheral components such as add-in boards 181a and 181b mounted on the mother board 171. In order to obtain sufficient space, the test apparatus 170 employs an extension board 174 inserted into a first socket 173 and a second socket 176. The test apparatus 170 further comprises an interconnection board 175 to test the memory module 15. The interface board 175 is fixed to the mother board 171 by fasteners 185. The test apparatus 170 is an improvement over the test apparatus 150 of FIG. 1. However, the structure increases the length of the contact points, and therefore, it is difficult to apply to high-speed products because it causes delay and/or distortion of the electrical signals. An additional problem with the test apparatus 170 is that it only provides week support for the test sockets 177.

At page 3, line 26 to page 4 line 3, please replace paragraph with the followings: